



### **SiW-ECAL overview**

Víncent Boudry

#### École polytechnique, Palaiseau





RESTIGE

RAL RESEARCH FELLOWSHI

#### CALICE Meeting Utrecht Uni 10/04/2019



TNA support + WP14





### An Ultra-Granular SiW-ECAL for experiments



Particle Flow optimised calorimetry

- Standard requirements
  - Hermeticity, Resolution, Uniformity & Stability (E, ( $\theta$ , $\varphi$ ), t)
- PFlow requirements:
  - Extremely high granularity
  - Compacity (density)

#### SiW+CFRC baseline choice for future Lepton Colliders:

- Tungsten as absorber material
  - $X_0 = 3.5 \text{ mm}, R_M = 9 \text{ mm}, \lambda_1 = 96 \text{ mm}$
  - Narrow showers
  - Assures compact design
- Silicon as active material
  - Support compact design: Sensor+RO≤2mm
  - Allows for ~any pixelisation
  - Robust technology
  - Excellent signal/noise ratio: ≥10
  - Intrinsic stability (vs environment, aging) Albeit expensive...
- Tungsten–Carbon alveolar structure
   Minimal structural dead-spaces
   Scalability



To be assessed

by prototypes

#### Not included: general services

### **SiW-ECAL Building blocks:** SLAB's & ASU's

#### R&D for "mass production" and QA

- Quality tests & preparation of large production
- Modularity → ASU & SLABs
- Choice of square wafers
  - (≠ from hex: SiD, CMS HGCAL)
- Numbers ( $R_{ECAL} = 1,8 \text{ m}, |Z_{Endcaps}|=2,35 \text{ m}$ ) (likely to be reduced by 30–40%)
  - Barrel modules: 40 (as of today all identical)
  - Endcap Modules: 24 (3 types)
  - ASUs = ~75,000
    - Wafers ~ 300,000 (2500 m<sup>2</sup>)
    - VFE chips ~ 1,200,000
    - Channels: 77Mch
  - Slabs = 6000 (B) + 3600 (EC) = 9600
    - $\neq$  lengths and endings



SiW-ECAL introduction | CALICE meeting | Utrecht uni, 10/04/2019 layout of a long slab Vincent.Boudry@in2p3.fr

Tests of

(1/4)

### SKIROC2 / 2A Analogue core



### **Silicon Sensors**

#### Cost driver

- ~30% of the total cost of the SiW-ECAL
  - ⇒ Units Cost reduction(CALIIMAX ANR program)
- Decoupling of Guard Ring (Square Events).
- new design of ILD detector
- Command Sensors (@ Hamamatsu)

  - direct contact with HPK engineers
  - Possibility of design for 8" in 186mm alveola **320, 550, 650** → 725 µm ?







Wafers glued onto PCB's



- "Square events"
  - cross talk between guard rings and pixels









'quantum unit' of ILD dimensions (here 6" wafer)

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### **Guard Ring Studies (HPK)**



Baby wafers: contig. & segmented Guard ring - 0, 1, 2, 4

- Floating 1 GR  $\Rightarrow$  'square events'
- − Addit'I GR  $\Rightarrow$  higher BD voltage

Cuts size ~ insensitive edge

- Cut size B = 500 µm
- Cut size C = 350 µm

Prelim Conclusions:

- − 320µm cut size C ✓
- 500 µm cut size B preferable

new 2018: 550 & 650 µm wafers

but HPK capacity for 8″ ≥2020



### ASU: 12 years of R&D



Most complex element: electro-mechanical integration

- Distrib / Collect signals from VFE (ASICs), Analog & Digital with dyn. range ≥ 7500
- Mechanical placer & holder for Wafers  $\rightarrow$  precision
- Thickness constraints





Milestone	Date	Object	Details	REM
1 <sup>st</sup> ASIC proto	2007	SK1 on FEV4	36 ch, 5 SCA	proto, lim @ 2000 mips
1 <sup>st</sup> ASIC	2009	SK2	64ch, 15 SCA	3000 mips
1 <sup>st</sup> prototype of a PCB	2010	FEV7	8 SK2	СОВ
1 <sup>st</sup> working PCB	2011	FEV8	16 SK2 (1024 ch)	CIP (QGFP)
1 <sup>st</sup> working ASU in BT	2012	FEV8	4 SK2 readout (256ch)	best S/N ~ 14 (HG), no PP retriggers 50– 75%
1 <sup>st</sup> run in PP	2013	FEV8-CIP		BGA, PP
1 <sup>st</sup> full ASU	2015	FEV10	4 units on test board 1024 channel	S/N ~ 17–18 (High Gain) retrigger ~ 50%
1 <sup>st</sup> SLABs	2016	FEV11	7 units	
pre-calo	2017	FEV 11	7 units	S/N ~ 20 (12) <sub>Trig,</sub> 6–8 % masked
1 <sup>st</sup> technological ECAL	2018	SLABvFEV11 & FEV13 SK2a+ Compact stack	SK2 & SK2a (⊃timing)	Improved S/N Timing

### **Assembly chain Paris**

#### To be improved and extended







6.00.4 **HR I PNHE** I A I Positioning and Gluing Cradle Dimension check Dimension check Functional Test Positioning and Gluing Dimension check Functional Test Dimension check Positioning and Gluing Wafer Raw PCB Dimension check Positioning and Gluing Dimension check Check of Cabling (ext) specifications Soldering Dimensions. Electrical (I, V, C), FEV Functional Test Dimensions check Visual aspect Electrical test Glue Deposition Positioning SLAB Gluing Validation tests Fixing Electrical testing ASU alidated SLAE ..... SiW-ECAL introduction | CALICE meeting | Utrecht uni, 10/04/2019

ASU 34, 13 oct 2015

• 100 • 101 • 102 • 108 • 108

'Simplified view'



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### **Mechanical Assembly for SLABs**

#### Assembly bench for:

- Fragile Wafer
- Precision of PCB's ~ 50 $\mu$ m
  - $\Rightarrow$  precision of 100µm on SLAB
- Interconnection

#### Connections to be handled by industry

- Dedicated Kaptons X
- Connectors
  - Grad-Conn
  - Antalec (near Orsay)

End of Slab and DAQ R&D

## Alignment tool **SL-board** Height: 1.5 mm (female) 1.27 - 1.5mm (male) Pin distance 1 mm Breton/Maalmi/Jeglot

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Jimmy

### Second assembly bench (FEV13) @ Kyushu







#### Gluing FEV and SMB to FPC © Taikan Suehara, Kyushu U.





Newly introduced automatic alignment (X-Y with camera and Z with laser)



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FEV placed manually

### **Beam-test 2015-2018**



### **COB SLABs for BT2019**

#### COB adaptations $\rightarrow$ for June BT

- Gluing of wafer(s) on COB PCB's [@LPNHE]
  - requires the adaptation of the gluing bench
- Testing of boards [@LAL]
  - requires the adaptation of the "versatile bench":
    - for GradConn Connectors

#### Work on assembly bench

- Check alignment option with connectors (was Kaptons)
- 2 producers:
  - GradConn
  - Antalec (near Orsay)

#### Improve testing procedures

 $\begin{array}{c} 40 \\ 20 \\ -20 \\ -20 \\ -20 \\ -40 \\ -80 \\ -60 \\ -60 \\ -80 \\ -60 \\ -80 \\ -60 \\ -60 \\ -80 \\ -80 \\ -60 \\ -60 \\ -80 \\ -$ 

Hits map, dif 1 1

Adrian

Roman



#### Electrical tests bench

- A dedicated electrical test system is used
  - to control the wafers before gluing
  - to check the short cuts immediately after gluing
  - to measure the I(V) curves of each wafer and all 4 wafers
- sourcemeter Keithley 2450 + LLR Bench



- · Gluing on HV Kapton & Soldering of
- 8 ASU's of 180.3 or 180.5 mm.
  in U-shape carbon-fibre cradle or
- on simple carbon plate. (181.4  $\pm$  0.3 mm)
- Alignment of two ASU wrt each other :±0.1 mm, Straightness deviation of 0.1 mm.
- In test phase with simplified ASU's
- using pick-and-place manipulator





### Rails, Cables & Pipes (Services)



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### **Active cooling**

R&D using CMS studies (Thanks to Th. Pierre-Emile from CMS-LLR group)

↓ ↓ ↓ ↓ P

### Passive cooling

#### Active cooling





Passive cooling ramp example

\_\_\_X



Active cooling set up test with water at room temperature

Active cooling test layout (400mm x 300mm x 3mm thick copper plate with 1,80D pipes embedded)

Passive cooling ramp set up test

### **Active cooling**

#### R&D using CMS studies (Thanks to Th. Pierre-Emile from CMS-LLR group)



Copper plate prototype dimensions information





S S

N.

П





Pipe insertion on a cooling prototype

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• Pipe insertion process introduces some efficiency loss due to the thermal contact resistance.

• The benefit remains significant with regard to a passive cooling



Thermal static CFD analysis thermal field example using Fluent with 100W extracted an water mass flow rate of 7g/s through 1,5mm ID pipe

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### **CFRP+W Structures**





### **Publications**

### **DESY-2017 Beam Test**

#### 7 SLAB's FEV11 $\supset$ 325 $\mu m$ Wafers

#### "Commissioning paper"

#### Editor: Adrián Irles

- submitted NIM + 2 ArXiv for openness:
  - short (~NIM) + long (arxiv only)
- Limited to «low energy» response: mip and noises
- Submitted to NIM (Jan. 2019):
  - Rebuttal from 2<sup>nd</sup> referee:
    - understood as already submitted to JINST (due to format of long arxiv paper and conf. paper).
    - ~clarified: goes through corrections  $\rightarrow$  June
  - Both ref for shower data as well
    - to be discussed

### Beam test performance of the highly granular SiW-ECAL technological prototype for the ILC.

K. Kawagoe<sup>a</sup>, Y. Miura<sup>a</sup>, I. Sekiya<sup>a</sup>, T. Suehara<sup>a</sup>, T. Yoshioka<sup>a</sup>, S. Bilokin<sup>b,\*</sup>, J. Bonis<sup>b</sup>, P. Cornebise<sup>b</sup>, A. Gallas<sup>b</sup>,
 <u>A. Irles</u><sup>b,\*\*</sup>, R. Pöschl<sup>b</sup>, F. Richard<sup>b</sup>, A. Thiebault<sup>b</sup>, D. Zerwas<sup>b</sup>, M. Anduze<sup>c</sup>, V. Balagura<sup>c</sup>, V. Boudry<sup>c</sup>, J-C. Brient<sup>c</sup>,
 E. Edy<sup>c</sup>, G. Fayolle<sup>c</sup>, M. Frotin<sup>c</sup>, F. Gastaldi<sup>c</sup>, R. Guillaumat<sup>c</sup>, A. Lobanov<sup>c</sup>, M. Louzir<sup>c</sup>, F. Magniette<sup>c</sup>, J. Nanni<sup>c</sup>,
 M. Rubio-Roy<sup>c,\*</sup>, K. Shpak<sup>c</sup>, H. Videau<sup>c</sup>, D. Yu<sup>c,d</sup>, S. Callier<sup>e</sup>, F. Dulucq<sup>e</sup>, Ch. de la Taille<sup>e</sup>, N. Seguin-Moreau<sup>e</sup>,
 J.E. Augustin<sup>f</sup>, R. Cornat<sup>f</sup>, J. David<sup>f</sup>, P. Ghislain<sup>f</sup>, D. Lacour<sup>f</sup>, L. Lavergne<sup>f,\*</sup>, J.M. Parraud<sup>f</sup>, J. S. Chai<sup>g</sup>, D. Jeans<sup>h</sup>

<sup>a</sup>Department of Physics and Research Center for Advanced Particle Physics, Kyushu University, 744 Motooka, Nishi-ku, Fukuoka 819-0395, Japan <sup>b</sup>Laboratoire de l'Accélerateur Linéaire (LAL), CNRS/IN2P3 et Université de Paris-Sud XI, Centre Scientifique d'Orsay Bâtiment 200, BP 34, F-91898 Orsay CEDEX, France <sup>c</sup>Laboratoire Leprince-Ringuet (LLR) – École polytechnique, CNRS/IN2P3, F-91128 Palaiseau Cedex, France <sup>d</sup>Institute of High Energy Physics of Beijing (IHEP), 19 Yuquan Rd, Shijingshan Qu, Beijing Shi, China <sup>e</sup>Laboratoire OMEGA – École polytechnique-CNRS/IN2P3, F-91128 Palaiseau Cedex, France <sup>f</sup>Laboratoire de Physique Nucléaire et de Hautes Energies (LPNHE), Université Sorbonne, UPD, CNRS/IN2P3, 4 Place Jussieu, 75005 Paris, France <sup>g</sup>Department of Electrical and Computer Engineering, Sungkyunkwan Universitiy, 16419, Suwon, Gyeonggi-do, Korea <sup>h</sup>Institute of Particle and Nuclear Studies, KEK, 1-1 Oho, Tsukuba, Ibaraki 305-0801, Japan

#### Abstract

The technological prototype of the CALICE highly granular silicon-tungsten electromagnetic calorimeter (SiW-ECAL) tested in beam at DESY in 2017. In this test the setup comprised seven layers of 1024 channels and a size of  $18 \times 18$  cm<sup>2</sup> each. This article presents key performance results in terms of signal over noise ratios at different levels of the readout chain and a study of the uniformity of the detector response.

Keywords: Calorimeter methods, calorimeters, Si and pad detectors

#### arxiv.org/abs/1902.00110

### **Conclusions & perspectives**

#### **Technical Milestones:**

#### At hand on CALICE prototype:

- Workable, scalable design
- Reduced GR event rates
- ASU with 1024 channel
  - » Signal/Noise > 10 (trigger), 20–30(ADC)
  - » on-going: HE e- response

#### On-going on ILD-like design

- Connection over 8 ASU's
- Mechanics & Cooling modelised
- Thicker & larger wafer (S/N ✓)
  - red. number of layers, dead zones
- Compact DAQ

#### Next steps

- Final chips (SK3-like): full 0-suppr ...
  - machine dependant (duty cycle, timing)
- Industrial aspects (components, aging, ...)
- Double Layered Long Slab Prototype
  - Design with larger wafers
  - Demonstrator for industry
    - Estimated cost ~160k€ / piece
  - ... Build a module-0 ...
  - ~13 DL-Long Slabs × 3–5
    - ... build a SIW-ECAL.

#### Ressources

... political dependant ...

### **Lessons from e-Long SLAB**

### Electric "long slab"

#### 2 weeks beg of July: full test of all prototypes:

- Electric long slab: 8 FEV12 + baby-wafers (320µm 2×2cm<sup>2</sup>):
- RC Filtering of HV between (every second) boards required
- Very clean response to "mip" (punch through e-)





### 1<sup>st</sup> 'electric long slab' (2018)

#### Support of interface boards + 12 ASUs (DBD)

-2+6+4 ASUs = -3.2 m

Plato from double

pixel crossing

**Trigger Threshold** 

**Error Function** 

Fit = modLG \* erf

 $modL(x,\mu,\sigma) = (1-c) * L(x,\mu,\sigma) + c * \int_{-}^{+\infty} \frac{L(t,\mu,\sigma)}{dt} dt$  $modLG = \int_{-\infty}^{+\infty} modL(t, \mu, \sigma) * G(x - t, \mu_G, \sigma_G) dt$ 

- Rotatably along long axis (for beam test) Rigidity :  $\leq \sim 1 \text{ mm per ASU}$
- Total access to upper and lower parts
  - 320µm Baby wafers (4×4 pixels) on the bottom ٠

LanGauss 1 MIP

LanGauss 2 MIPs

Fit with Mod LanGau function



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114123

190.8

97.49

393.7/339 10.58 ± 0.18 38.8 ± 0.1 2 62de+05 + 1 373e+01 6596 ± 0.0331

384 + 1 23

6.066e+04 + 1.892e+03 0 2541+0 002

BMS

72/100

GSign Wirth

Errentre

145

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2.52

2.51

2.50

2.49 2.48

2.47

2.46

### **MIP** response vs position

#### mip MPV \*cos(θ) vs ASU#

- OK for 4 1<sup>st</sup> ASU's + Small drop ~of signal ~2%/ASU for  $\geq$  ASU#5
- Also hints similar drop on  $\sigma_{\text{ped}}$ 
  - $\Rightarrow$  Voltage or Gain drop ? Power pulsed mode with ballast et end of slab or just random build-up effect from chip variability?
  - Answer: Voltage + Band-gap variability ٠ Data fitted with
    - linear voltage drop (vs distance) —
    - BG variability \_

#### Presented @ VCI'2019; paper submitted march 2019

 $\supset$  ack't of support from AIDA-2020 and P2IO



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### Going to 200mm Wafers...

From CMS HGCAL development & Hamamatsu contacts future is 200mm (8") ingots, 725µm thickness

Mechanical constraints  $\rightarrow$  ~187 mm alveoli, ~12 cm wafer

→ 1.5 Wafers  $\otimes$  cell # mult. of 3  $\otimes$  cell width ~5 mm  $\otimes$  paving with ~64ch ASICs → <u>30</u> or 36 cells in width

#### Optimised ReadOut electronics



- ASU: 1440 pads, 24 ASICs
- Noise ~ C ~ width²/th. ~ cst, Signal ~ th ◄, S/N ~ ×1.5; depl. Voltage ~ th² (×2)
   ⇒ Improved timing perf (esp. for mips)

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121.19

294.05

60.59



wafers on 200mm ingot ; 63 % use of surface



35

# BACK-UP

### **Redefinition of dimensions**

- Full costing (hardware and man-power) and integration planning done by Henri Videau
- 3 designs looked at

under work version of **ECal Technical Design Document** (TDD, ~100 pages) by Henri Videau (LLR), Marc Anduze (LLR) and Denis Grondin (LPSC)

- a "baseline" (or "large") with inner ECal radius at RECal =1804mm, (model close to the DBD) with 30 layers
- a "small ILD" model RECal ~1500 mm (all related quantities adapted  $\leftrightarrow R_{outer}^{Endcaps}$ )
- a model with slightly reduced number of layers = 26 layers
- 725µm thickness with 200mm (8") wafers ; 5.08  $\rightarrow$  6mm cell size
  - ~ identical photon resolution expected
  - 13% gain cost on Silicon surface, PCB, and 40% on electronics (and power consumption) wrt DBD
  - Improved S/N ratio & timing, less channeling @ 90°

Tiling



### FEV13

#### Only a few masked channels!

- worked «out of box»

#### but instabilities after a couple of days

- 4 new layers produced in Kyushu.
  - 3× 650 µm + 1 × 320 µm wafers

#### improved S/N handling, TDC enabling

- individual thr adj.
- better noise adjustment  $\rightarrow$  ~ only ch 37 excluded



### **FEV13** assembly in Japan



#### Similar to production in Paris region (AIDA-2020 benches)





We can get data now !

But we have to finish to acquire datas in 4 times, because we have to test 5 SLABs. We already finished only the SLAB.

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S/N ratio is about 30. Improved to 40 in some

cases

### Stack: S/N on the trigger line from thr. scan



Injected signal  $\rightarrow$  MIP

S/N ~ 20 in ADC branch S/N ~ 12 in Trigger Branch. Trigger at 50% mip with 6σ or 1/3 mip with 4σ

### S/N in the trigger line

- For autotrigger data taking, a S/N is to be defined by the study of the trigger line (fast shaper in Skiroc) → threshold scans with different signals
  - The threshold scan curve is interpreted as the integral of the gaussian distribution of the noise.



### **Combined BT at CERN 2018**



- 37 layers of SDHCAL RPC, 5MHz clock
- 10 layer of SiW-ECAL : 6 FEV11 and 4 FEV13.
  - 2.5 MHz (all FEV11 but 1) and 5.0 MHz (FEV13+1FEV11)
  - many issues with FEV13:
    - partial commissioning at LLR bef. BT
    - insecure transport (in plane)  $\rightarrow$  repair on-site, esp. HV connections
  - 1 FEV13 has been working reliably



### **Standalone runs**



#### Muons and electrons run

These are the statistics for electron data. Obtained from the zbarycenter vs nhits plots.

- low contamination, except @ High E.
- shower analysis still to be done (also for DESY tests)

energy	total events	electrons shower like events
10 GeV	630	~630 (very low contamination)
20 GeV	4060	~3480
40 GeV	2023	~1800
80 GeV	19420	~8000
150 GeV	8474	~1000

### **CERN-2018** Combined runs

#### Required some work on DAQ:

- HW and SW synchronisation
- Solution of CERN-2016 + 40 MHz clock on both
- first combined test this week (since 2016) but very limited manpower availability
  - shared Spills (and event number), separate clocks

#### **Reconstruction:**

- Data:
  - ECAL = #sp, #bx\_e
  - SDHCAL = cc (absolute bx@sp\_start), #sp, #bx\_h
- Procedure (to be done)
  - 1. Extract cc form SDHCAL event
  - 2. rec. times in ECAL and HCAL
    - time\_in\_sp = cc + f\_freq \*  $\#bx_i + \Delta s$
  - 3. check linarities ( $\Delta f + \Delta syst.$ )
  - 4. rec. ECAL + HCAL

- Selection: nslabs\_with\_hit≥3
- Plot for PiPlus\_50GeV (offset from e-log)

#### VERY PRELIMINARY

Common runs (selection = nslabs with hit >3)					
run	events (offsets elog)	events (offsets twiki)			
PiPlus_40GeV	28299	not calculated			
PiPlus_50GeV	3241	not calculated			
PiPlus_60GeV	2365	not calculated			
PiPlus_70GeV	12727	not calculated			
PiPlus_80GeV	5484	not calculated			
Muon_200GeV	108729	89506			
Electron 150 GeV	not copied to the cern eos				
Standalone last muon ruon	not copied to	the cern eos			



"Some direct coincidences"



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1<sup>st</sup> common meet 18/12/18

### **Other news**

#### FEV13 with improved mechanics

(FEV13 slab dismounted and repaired in Kyushu)

- all HV faults due to repairs

#### 2 weeks of BT at DESY in 2019:

- 24/06 07/07/2019
  - COB tests
  - FEV13



DESY Test Beam Schedule 2019 - Version 2 15/11/2018

X

X

X

TB24/1

PCMAG

T2K

T2K

CALICE-SIW-ECAL

CALICE-SIW-ECAL

**TB22** 

ATLAS-ITk-Strips

ATLAS-ITk-Strips

AFP-TOF

Mu3e



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Week

28

10-Jun-19

17-Jun-19

24-Jun-19

1-Jul-15

8-Jul-1

15-Jul-19

22-Jul-19

evners, Marcel Stanitzki - DESY Test Ream Coordinators

X

X

x

x

X

TB21

CLIC PIXEL

TBMST

CMS-Pixel-Phase2

CMS-Pixel-Phase2

GammaMeV

CLIC PIXEL

X-Ray-Crystal-Rad